

Application/Control No.	Applicant(s)/Patent under Reexamination
10/664,772	MASEL ET AL.
Examiner	Art Unit
Dah-Wei D. Yuan	1745

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SEARCHED					
Class	Subclass	Date	Examiner		
429	12	4/24/2006	ĐWY		
429	25	4/24/2006	DWY		
429	34	4/24/2006	DWY		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST	4/24/2006	DWY
STN	4/24/2006	DWY
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